

ESD5V0D3

Description

ESD5V0D3 is designed to protect voltage sensitive components from ESD and transient voltage events. Excellent clamping capability, low leakage, and fast response time, make these parts ideal for ESD protection on designs where board space is at a premium. Because of its small size, it is suited for use in cellular phones, MP3 players, digital cameras and many other portable applications where board space is at a premium

Features

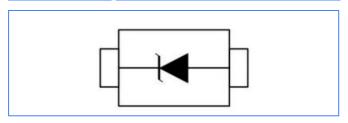
- Ultra low leakage: nA levelOperating voltage: 5V
- Package: SOD-323
- Low clamping voltage
- Complies with following standards:
 - IEC 61000-4-2 (ESD) immunity test

Air discharge: ±15kV Contact discharge: ±8kV

- IEC61000-4-4 (EFT) 40A (5/50ns)
- IEC61000-4-5 (Lightning) 12A (8/20μs)



Functional Diagram



Applications

- Cell Phone Handsets and Accessories
- Microprocessor based equipment
- Personal Digital Assistants (PDA's)
- Notebooks, Desktops, and Servers
- Portable Instrumentation
- Peripherals
- Pagers

Absolute Maximum Ratings(Tamb=25°C unless otherwise specified)

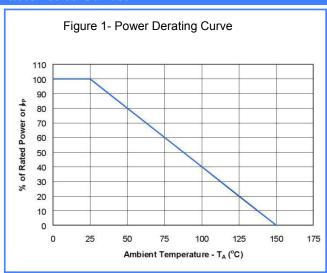
Parameter	Symbol	Value	Unit
Peak Pulse Power (8/20µs)	P _{PP}	350	Watts
ESD per IEC 61000-4-2 (Air)		±15	KV
ESD per IEC 61000-4-2 (Contact)	V _{ESD}	±8	KV
Lead Soldering Temperature	T∟	260 (10 sec)	°C
Operating Temperature Range	T₃	T _J -55 to +150	
Storage Temperature Range	Т _{втл}	-55 to +150	°C

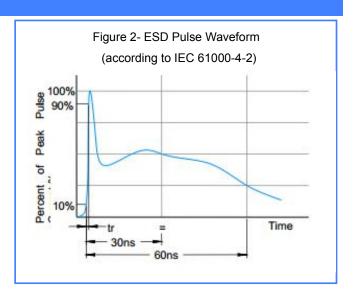


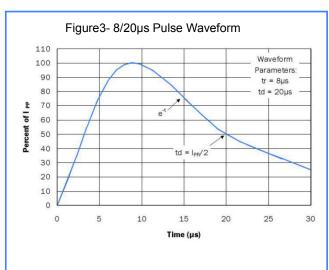
Electrical Characteristics (TA = 25 °C unless otherwise noted)

Parameter	Symbol	Conditions	Min.	Тур.	Max.	Units
Reverse Stand-off Voltage	$V_{\scriptscriptstyle RWM}$				5	V
Reverse Breakdown Voltage	$V_{\scriptscriptstyle BR}$	I _t = 1mA	6			V
Reverse Leakage Current	I _R	V _R =V _{RWM}			10	μΑ
Clamping Voltage	Vc	$I_{PP}=1A$, $t_{P}=8/20\mu s$			9.8	V
		I_{PP} =24A, t_{P} = 8/20 μ s			13.5	V
Junction Capacitance	C	V_R =0V, f = 1MHz			350	pF

Characteristics Curves

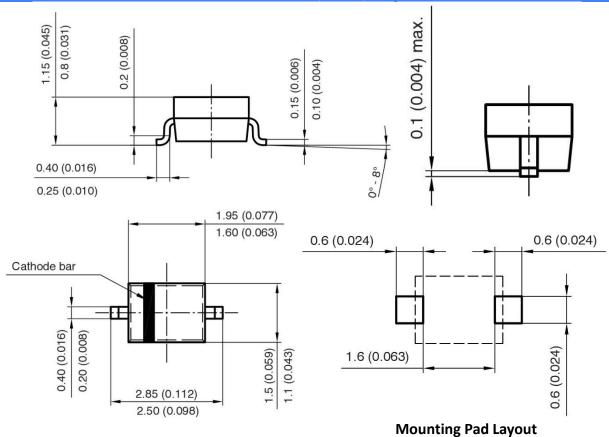












Disclaimer

Specifications are subject to change without notice.

The device characteristics and parameters in this data sheet can and do vary in different applications and actual device performance may vary over time.

Users should verify actual device performance in their specific applications.